



Welcome to [E-XFL.COM](https://www.e-xfl.com)

### What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

### Applications of "[Embedded - Microcontrollers](#)"

#### Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	80MHz
Connectivity	CANbus, I <sup>2</sup> C, IrDA, LINbus, MMC/SD, QSPI, SAI, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, DMA, PWM, WDT
Number of I/O	52
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	160K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 3.6V
Data Converters	A/D 16x12b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/stmicroelectronics/stm32l452ret3">https://www.e-xfl.com/product-detail/stmicroelectronics/stm32l452ret3</a>

Table 82.	ADC accuracy - limited test conditions 4	160
Table 83.	DAC characteristics	163
Table 84.	DAC accuracy	166
Table 85.	VREFBUF characteristics	168
Table 86.	COMP characteristics	170
Table 87.	OPAMP characteristics	171
Table 88.	TS characteristics	174
Table 89.	V <sub>BAT</sub> monitoring characteristics	175
Table 90.	V <sub>BAT</sub> charging characteristics	175
Table 91.	TIMx characteristics	175
Table 92.	IWDG min/max timeout period at 32 kHz (LSI)	176
Table 93.	WWDG min/max timeout value at 80 MHz (PCLK)	176
Table 94.	I2C analog filter characteristics	177
Table 95.	SPI characteristics	178
Table 96.	Quad SPI characteristics in SDR mode	181
Table 97.	QUADSPI characteristics in DDR mode	182
Table 98.	SAI characteristics	184
Table 99.	SD / MMC dynamic characteristics, VDD=2.7 V to 3.6 V	186
Table 100.	eMMC dynamic characteristics, VDD = 1.71 V to 1.9 V	187
Table 101.	USB electrical characteristics	188
Table 102.	LQFP100 - 100-pin, 14 x 14 mm low-profile quad flat package mechanical data	189
Table 103.	UFBGA100 - 100-ball, 7 x 7 mm, 0.50 mm pitch, ultra fine pitch ball grid array package mechanical data	192
Table 104.	UFBGA100 recommended PCB design rules (0.5 mm pitch BGA)	193
Table 105.	LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat package mechanical data	195
Table 106.	UFBGA64 – 64-ball, 5 x 5 mm, 0.5 mm pitch ultra profile fine pitch ball grid array package mechanical data	198
Table 107.	UFBGA64 recommended PCB design rules (0.5 mm pitch BGA)	198
Table 108.	WLCSP64 - 64-ball, 3.357x3.657 mm 0.4 mm pitch wafer level chip scale mechanical data	201
Table 109.	WLCSP64 recommended PCB design rules (0.4 mm pitch)	202
Table 110.	UFQFPN48 - 48-lead, 7x7 mm, 0.5 mm pitch, ultra thin fine pitch quad flat package mechanical data	204
Table 111.	Package thermal characteristics	206
Table 112.	STM32L452xx ordering information scheme	209
Table 113.	Document revision history	210

# 1 Introduction

This datasheet provides the ordering information and mechanical device characteristics of the STM32L452xx microcontrollers.

This document should be read in conjunction with the STM32L43xxx/44xxx/45xxx/46xxx reference manual (RM0394). The reference manual is available from the STMicroelectronics website [www.st.com](http://www.st.com).

For information on the Arm<sup>®(a)</sup> Cortex<sup>®</sup>-M4 core, please refer to the Cortex<sup>®</sup>-M4 Technical Reference Manual, available from the [www.arm.com](http://www.arm.com) website.



arm

---

a. Arm is a registered trademark of Arm Limited (or its subsidiaries) in the US and/or elsewhere.

**Table 2. STM32L452xx family device features and peripheral counts (continued)**

Peripheral	STM32L452Vx	STM32L452Rx	STM32L452Cx
Operating voltage	1.71 to 3.6 V		
Operating temperature	Ambient operating temperature: -40 to 85 °C / -40 to 125 °C Junction temperature: -40 to 105 °C / -40 to 130 °C		
Packages	LQFP100 UFBGA100	WLCSP64 LQFP64 UFBGA64	UFQFPN48

1. WKUP5, ADC1\_IN14 and SDMMC interface are not supported by 64-pin packages with SMPS option.
2. In case external SMPS package type is used, 2 GPIO's are replaced by VDD12 pins to connect the SMPS power supplies hence reducing the number of available GPIO's by 2.

The whole non-volatile memory embeds the error correction code (ECC) feature supporting:

- single error detection and correction
- double error detection.
- The address of the ECC fail can be read in the ECC register

### 3.5 Embedded SRAM

STM32L452xx devices feature 160 Kbyte of embedded SRAM. This SRAM is split into two blocks:

- 128 Kbyte mapped at address 0x2000 0000 (SRAM1)
- 32 Kbyte located at address 0x1000 0000 with hardware parity check (SRAM2).

This memory is also mapped at address 0x2002 0000, offering a contiguous address space with the SRAM1 (32 Kbyte aliased by bit band)

This block is accessed through the ICode/DCode buses for maximum performance. These 32 Kbyte SRAM can also be retained in Standby mode.

The SRAM2 can be write-protected with 1 Kbyte granularity.

The memory can be accessed in read/write at CPU clock speed with 0 wait states.

### 3.6 Firewall

The device embeds a Firewall which protects code sensitive and secure data from any access performed by a code executed outside of the protected areas.

Each illegal access generates a reset which kills immediately the detected intrusion.

The Firewall main features are the following:

- Three segments can be protected and defined thanks to the Firewall registers:
  - Code segment (located in Flash or SRAM1 if defined as executable protected area)
  - Non-volatile data segment (located in Flash)
  - Volatile data segment (located in SRAM1)
- The start address and the length of each segments are configurable:
  - Code segment: up to 1024 Kbyte with granularity of 256 bytes
  - Non-volatile data segment: up to 1024 Kbyte with granularity of 256 bytes
  - Volatile data segment: up to 128 Kbyte with a granularity of 64 bytes
- Specific mechanism implemented to open the Firewall to get access to the protected areas (call gate entry sequence)
- Volatile data segment can be shared or not with the non-protected code
- Volatile data segment can be executed or not depending on the Firewall configuration

The Flash readout protection must be set to level 2 in order to reach the expected level of protection.

Table 5. Functionalities depending on the working mode<sup>(1)</sup>

Peripheral	Run	Sleep	Low-power run	Low-power sleep	Stop 0/1		Stop 2		Standby		Shutdown		VBAT
					-	Wakeup capability	-	Wakeup capability	-	Wakeup capability	-	Wakeup capability	
CPU	Y	-	Y	-	-	-	-	-	-	-	-	-	-
Flash memory (up to 512 KB)	O <sup>(2)</sup>	O <sup>(2)</sup>	O <sup>(2)</sup>	O <sup>(2)</sup>	-	-	-	-	-	-	-	-	-
SRAM1 (128 KB)	Y	Y <sup>(3)</sup>	Y	Y <sup>(3)</sup>	Y	-	Y	-	-	-	-	-	-
SRAM2 (32 KB)	Y	Y <sup>(3)</sup>	Y	Y <sup>(3)</sup>	Y	-	Y	-	O <sup>(4)</sup>	-	-	-	-
Quad SPI	O	O	O	O	-	-	-	-	-	-	-	-	-
Backup Registers	Y	Y	Y	Y	Y	-	Y	-	Y	-	Y	-	Y
Brown-out reset (BOR)	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	-	-	-
Programmable Voltage Detector (PVD)	O	O	O	O	O	O	O	O	-	-	-	-	-
Peripheral Voltage Monitor (PVMx; x=1,3,4)	O	O	O	O	O	O	O	O	-	-	-	-	-
DMA	O	O	O	O	-	-	-	-	-	-	-	-	-
High Speed Internal (HSI16)	O	O	O	O	(5)	-	(5)	-	-	-	-	-	-
Oscillator RC48	O	O	-	-	-	-	-	-	-	-	-	-	-
High Speed External (HSE)	O	O	O	O	-	-	-	-	-	-	-	-	-
Low Speed Internal (LSI)	O	O	O	O	O	-	O	-	O	-	-	-	-
Low Speed External (LSE)	O	O	O	O	O	-	O	-	O	-	O	-	O
Multi-Speed Internal (MSI)	O	O	O	O	-	-	-	-	-	-	-	-	-
Clock Security System (CSS)	O	O	O	O	-	-	-	-	-	-	-	-	-
Clock Security System on LSE	O	O	O	O	O	O	O	O	O	O	-	-	-
RTC / Auto wakeup	O	O	O	O	O	O	O	O	O	O	O	O	O
Number of RTC Tamper pins	3	3	3	3	3	O	3	O	3	O	3	O	3

**Table 17. Alternate function AF0 to AF7<sup>(1)</sup> (continued)**

Port		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7
		SYS_AF	TIM1/TIM2 LPTIM1	I2C4/TIM1/ TIM2/TIM3	I2C4/USART2/ CAN1/TIM1	I2C1/I2C2/ I2C3/I2C4	SPI1/SPI2/I2C4	SPI3/DFSDM/ COMP1	USART1/ USART2/ USART3
Port H	PH0	-	-	-	-	-	-	-	-
	PH1	-	-	-	-	-	-	-	-
	PH3	-	-	-	-	-	-	-	-

1. Please refer to [Table 18](#) for AF8 to AF15.

1. All values are obtained by calculation based on measurements done without SMPS and using following parameters:  
SMPS input = 3.3 V, SMPS efficiency = 85%,  $V_{DD12} = 1.10$  V
2. Reduced code used for characterization results provided in [Table 27](#), [Table 29](#), [Table 31](#).

**Table 35. Typical current consumption in Run, with different codes running from Flash, ART enable (Cache ON Prefetch OFF) and power supplied by external SMPS ( $V_{DD12} = 1.05$  V)**

Symbol	Parameter	Conditions <sup>(1)</sup>			TYP	Unit	TYP	Unit
		-	Voltage scaling	Code	25 °C		25 °C	
$I_{DD\_ALL}$ (Run)	Supply current in Run mode	$f_{HCLK} = f_{HSE}$ up to 48 MHz included, bypass mode PLL ON above 48 MHz all peripherals disable	$f_{HCLK} = 26$ MHz	Reduced code <sup>(2)</sup>	0.92	mA	36	$\mu A/MHz$
				Coremark	1.04		40	
				Dhrystone 2.1	1.08		42	
				Fibonacci	1.02		39	
				While(1)	0.92		36	

1. All values are obtained by calculation based on measurements done without SMPS and using following parameters:  
SMPS input = 3.3 V, SMPS efficiency = 85%,  $V_{DD12} = 1.05$  V
2. Reduced code used for characterization results provided in [Table 27](#), [Table 29](#), [Table 31](#).



**Table 36. Typical current consumption in Run and Low-power run modes, with different codes running from Flash, ART disable**

Symbol	Parameter	Conditions			TYP	Unit	TYP	Unit
		-	Voltage scaling	Code	25 °C		25 °C	
$I_{DD\_ALL}$ (Run)	Supply current in Run mode	$f_{HCLK} = f_{HSE}$ up to 48 MHz included, bypass mode PLL ON above 48 MHz all peripherals disable	Range 2 $f_{HCLK} = 26$ MHz	Reduced code <sup>(1)</sup>	2.75	mA	106	$\mu A/MHz$
				Coremark	2.50		96	
				Dhrystone 2.1	2.50		96	
				Fibonacci	2.30		88	
				While(1)	2.20		84.6	
			Range 1 $f_{HCLK} = 80$ MHz	Reduced code <sup>(1)</sup>	8.85	mA	111	$\mu A/MHz$
				Coremark	8.15		102	
				Dhrystone 2.1	8.15		102	
				Fibonacci	7.55		94	
				While(1)	7.95		99	
$I_{DD\_ALL}$ (LPRun)	Supply current in Low-power run	$f_{HCLK} = f_{MSI} = 2$ MHz all peripherals disable		Reduced code <sup>(1)</sup>	340	$\mu A$	170	$\mu A/MHz$
				Coremark	380		190	
				Dhrystone 2.1	355		178	
				Fibonacci	355		178	
				While(1)	405		203	

1. Reduced code used for characterization results provided in [Table 27](#), [Table 29](#), [Table 31](#).

**Table 37. Typical current consumption in Run modes, with different codes running from Flash, ART disable and power supplied by external SMPS ( $V_{DD12} = 1.10$  V)**

Symbol	Parameter	Conditions <sup>(1)</sup>			TYP	Unit	TYP	Unit
		-	Voltage scaling	Code	25 °C		25 °C	
$I_{DD\_ALL}$ (Run)	Supply current in Run mode	$f_{HCLK} = f_{HSE}$ up to 48 MHz included, bypass mode PLL ON above 48 MHz all peripherals disable	$f_{HCLK} = 26$ MHz	Reduced code <sup>(2)</sup>	1.19	mA	46	$\mu A/MHz$
				Coremark	1.08		41	
				Dhrystone 2.1	1.08		41	
				Fibonacci	0.99		38	
				While(1)	0.95		37	
			$f_{HCLK} = 80$ MHz	Reduced code <sup>(2)</sup>	3.18		40	
				Coremark	2.93		37	
				Dhrystone 2.1	2.93		37	
				Fibonacci	2.71		34	
				While(1)	2.86		36	

1. All values are obtained by calculation based on measurements done without SMPS and using following parameters: SMPS input = 3.3 V, SMPS efficiency = 85%,  $V_{DD12} = 1.10$  V

2. Reduced code used for characterization results provided in [Table 27](#), [Table 29](#), [Table 31](#).

**Table 38. Typical current consumption in Run modes, with different codes running from Flash, ART disable and power supplied by external SMPS ( $V_{DD12} = 1.05$  V)**

Symbol	Parameter	Conditions <sup>(1)</sup>			TYP	Unit	TYP	Unit
		-	Voltage scaling	Code	25 °C		25 °C	
$I_{DD\_ALL}$ (Run)	Supply current in Run mode	$f_{HCLK} = f_{HSE}$ up to 48 MHz included, bypass mode PLL ON above 48 MHz all peripherals	$f_{HCLK} = 26$ MHz	Reduced code <sup>(2)</sup>	1.08	mA	42	$\mu A/MHz$
				Coremark	0.98		38	
				Dhrystone 2.1	0.98		38	
				Fibonacci	0.90		35	
				While(1)	0.86		33	

1. All values are obtained by calculation based on measurements done without SMPS and using following parameters: SMPS input = 3.3 V, SMPS efficiency = 85%,  $V_{DD12} = 1.05$  V
2. Reduced code used for characterization results provided in [Table 27](#), [Table 29](#), [Table 31](#).

**Table 39. Typical current consumption in Run and Low-power run modes, with different codes running from SRAM1**

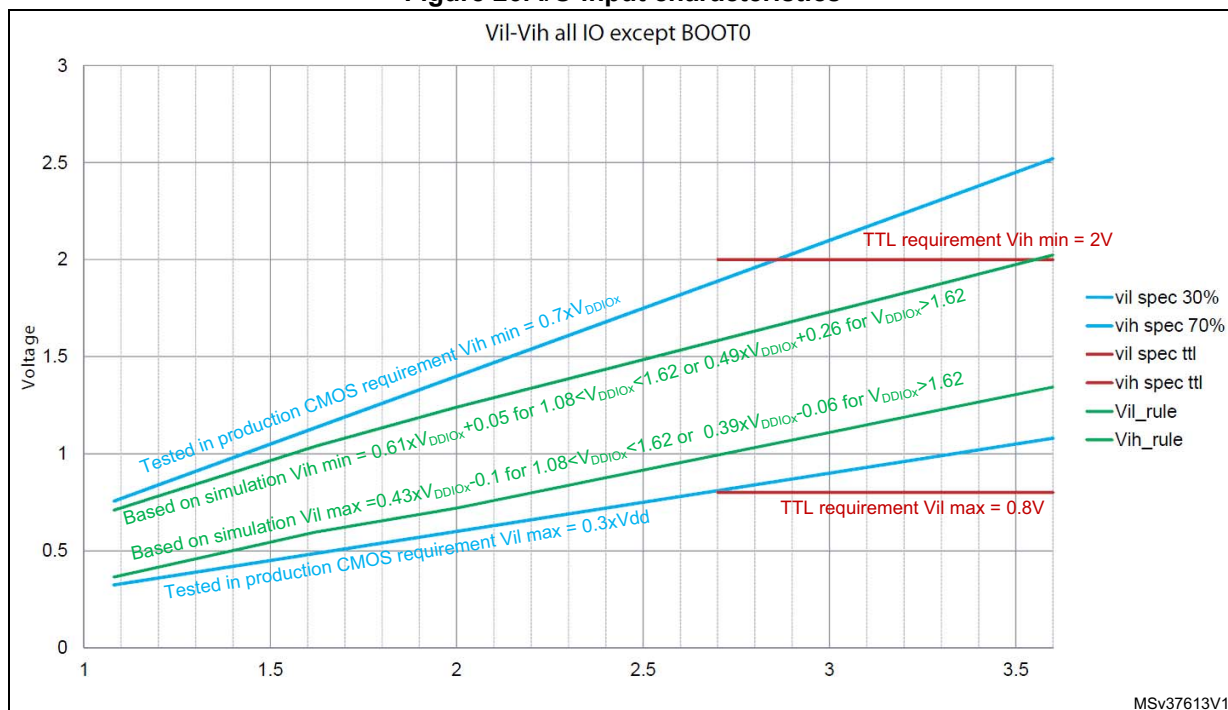
Symbol	Parameter	Conditions			TYP	Unit	TYP	Unit
		-	Voltage scaling	Code	25 °C		25 °C	
$I_{DD\_ALL}$ (Run)	Supply current in Run mode	$f_{HCLK} = f_{HSE}$ up to 48 MHz included, bypass mode PLL ON above 48 MHz all peripherals disable	Range 2 $f_{HCLK} = 26$ MHz	Reduced code <sup>(1)</sup>	2.40	mA	92	$\mu A/MHz$
				Coremark	2.20		85	
				Dhrystone 2.1	2.35		90	
				Fibonacci	2.20		85	
				While(1)	2.30		88	
			Range 1 $f_{HCLK} = 80$ MHz	Reduced code <sup>(1)</sup>	8.55	mA	107	$\mu A/MHz$
				Coremark	7.75		97	
				Dhrystone 2.1	8.45		106	
				Fibonacci	7.80		98	
				While(1)	8.75		109	
$I_{DD\_ALL}$ (LPRun)	Supply current in Low-power run	$f_{HCLK} = f_{MSI} = 2$ MHz all peripherals disable		Reduced code <sup>(1)</sup>	220	$\mu A$	110	$\mu A/MHz$
				Coremark	190		95	
				Dhrystone 2.1	215		108	
				Fibonacci	200		100	
				While(1)	210		105	

1. Reduced code used for characterization results provided in [Table 27](#), [Table 29](#), [Table 31](#).

1. Refer to [Figure 26: I/O input characteristics](#).
2. Tested in production.
3. Guaranteed by design.
4. All FT\_xx IO except FT\_u and PC3 I/O.
5.  $\text{Max}(V_{DDXX})$  is the maximum value of all the I/O supplies.
6. To sustain a voltage higher than  $\text{Min}(V_{DD}, V_{DDA}, V_{DDUSB}) + 0.3 \text{ V}$ , the internal Pull-up and Pull-Down resistors must be disabled.
7. This value represents the pad leakage of the IO itself. The total product pad leakage is provided by this formula:  
 $I_{\text{Total\_leak\_max}} = 10 \mu\text{A} + [\text{number of IOs where } V_{IN} \text{ is applied on the pad}] \times I_{\text{kg}}(\text{Max})$ .
8. Pull-up and pull-down resistors are designed with a true resistance in series with a switchable PMOS/NMOS. This PMOS/NMOS contribution to the series resistance is minimal (~10% order).

All I/Os are CMOS- and TTL-compliant (no software configuration required). Their characteristics cover more than the strict CMOS-technology or TTL parameters. The coverage of these requirements is shown in [Figure 26](#) for standard I/Os, and in [Figure 26](#) for 5 V tolerant I/Os.

**Figure 26. I/O input characteristics**



### Output driving current

The GPIOs (general purpose input/outputs) can sink or source up to  $\pm 8 \text{ mA}$ , and sink or source up to  $\pm 20 \text{ mA}$  (with a relaxed  $V_{OL}/V_{OH}$ ).

Table 77. ADC characteristics<sup>(1) (2)</sup> (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$t_{LATR}$	Trigger conversion latency Regular and injected channels without conversion abort	CKMODE = 00	1.5	2	2.5	$1/f_{ADC}$
		CKMODE = 01	-	-	2.0	
		CKMODE = 10	-	-	2.25	
		CKMODE = 11	-	-	2.125	
$t_{LATRINJ}$	Trigger conversion latency Injected channels aborting a regular conversion	CKMODE = 00	2.5	3	3.5	$1/f_{ADC}$
		CKMODE = 01	-	-	3.0	
		CKMODE = 10	-	-	3.25	
		CKMODE = 11	-	-	3.125	
$t_s$	Sampling time	$f_{ADC} = 80 \text{ MHz}$	0.03125	-	8.00625	$\mu\text{s}$
		-	2.5	-	640.5	$1/f_{ADC}$
$t_{ADCVREG\_STUP}$	ADC voltage regulator start-up time	-	-	-	20	$\mu\text{s}$
$t_{CONV}$	Total conversion time (including sampling time)	$f_{ADC} = 80 \text{ MHz}$ Resolution = 12 bits	0.1875	-	8.1625	$\mu\text{s}$
		Resolution = 12 bits	$t_s + 12.5$ cycles for successive approximation = 15 to 653			$1/f_{ADC}$
$I_{DDA}(ADC)$	ADC consumption from the $V_{DDA}$ supply	$f_s = 5 \text{ Msps}$	-	730	830	$\mu\text{A}$
		$f_s = 1 \text{ Msps}$	-	160	220	
		$f_s = 10 \text{ ksps}$	-	16	50	
$I_{DDV\_S}(ADC)$	ADC consumption from the $V_{REF+}$ single ended mode	$f_s = 5 \text{ Msps}$	-	130	160	$\mu\text{A}$
		$f_s = 1 \text{ Msps}$	-	30	40	
		$f_s = 10 \text{ ksps}$	-	0.6	2	
$I_{DDV\_D}(ADC)$	ADC consumption from the $V_{REF+}$ differential mode	$f_s = 5 \text{ Msps}$	-	260	310	$\mu\text{A}$
		$f_s = 1 \text{ Msps}$	-	60	70	
		$f_s = 10 \text{ ksps}$	-	1.3	3	

1. Guaranteed by design
2. The I/O analog switch voltage booster is enable when  $V_{DDA} < 2.4 \text{ V}$  (BOOSTEN = 1 in the SYSCFG\_CFGR1 when  $V_{DDA} < 2.4\text{V}$ ). It is disable when  $V_{DDA} \geq 2.4 \text{ V}$ .
3.  $V_{REF+}$  can be internally connected to  $V_{DDA}$  and  $V_{REF-}$  can be internally connected to  $V_{SSA}$ , depending on the package. Refer to [Section 4: Pinouts and pin description](#) for further details.

The maximum value of  $R_{AIN}$  can be found in [Table 78: Maximum ADC RAIN](#).

Table 79. ADC accuracy - limited test conditions 1<sup>(1)</sup>(2)(3) (continued)

Sym- bol	Parameter	Conditions <sup>(4)</sup>			Min	Typ	Max	Unit
THD	Total harmonic distortion	ADC clock frequency ≤ 80 MHz, Sampling rate ≤ 5.33 Msps, V <sub>DDA</sub> = V <sub>REF+</sub> = 3 V, TA = 25 °C	Single ended	Fast channel (max speed)	-	-74	-73	dB
				Slow channel (max speed)	-	-74	-73	
			Differential	Fast channel (max speed)	-	-79	-76	
				Slow channel (max speed)	-	-79	-76	

1. Guaranteed by design.
2. ADC DC accuracy values are measured after internal calibration.
3. ADC accuracy vs. negative Injection Current: Injecting negative current on any analog input pins should be avoided as this significantly reduces the accuracy of the conversion being performed on another analog input. It is recommended to add a Schottky diode (pin to ground) to analog pins which may potentially inject negative current.
4. The I/O analog switch voltage booster is enable when V<sub>DDA</sub> < 2.4 V (BOOSTEN = 1 in the SYSCFG\_CFGR1 when V<sub>DDA</sub> < 2.4 V). It is disable when V<sub>DDA</sub> ≥ 2.4 V. No oversampling.

## 6.3.20 Voltage reference buffer characteristics

Table 85. VREFBUF characteristics<sup>(1)</sup>

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
$V_{DDA}$	Analog supply voltage	Normal mode	$V_{RS} = 0$	2.4	-	3.6	V
			$V_{RS} = 1$	2.8	-	3.6	
		Degraded mode <sup>(2)</sup>	$V_{RS} = 0$	1.65	-	2.4	
			$V_{RS} = 1$	1.65	-	2.8	
$V_{REFBUF\_OUT}$	Voltage reference output	Normal mode	$V_{RS} = 0$	2.046 <sup>(3)</sup>	2.048	2.049 <sup>(3)</sup>	
			$V_{RS} = 1$	2.498 <sup>(3)</sup>	2.5	2.502 <sup>(3)</sup>	
		Degraded mode <sup>(2)</sup>	$V_{RS} = 0$	$V_{DDA} - 150 \text{ mV}$	-	$V_{DDA}$	
			$V_{RS} = 1$	$V_{DDA} - 150 \text{ mV}$	-	$V_{DDA}$	
TRIM	Trim step resolution	-	-	-	$\pm 0.05$	$\pm 0.1$	%
CL	Load capacitor	-	-	0.5	1	1.5	$\mu\text{F}$
esr	Equivalent Serial Resistor of Cloud	-	-	-	-	2	$\Omega$
$I_{load}$	Static load current	-	-	-	-	4	mA
$I_{line\_reg}$	Line regulation	$2.8 \text{ V} \leq V_{DDA} \leq 3.6 \text{ V}$	$I_{load} = 500 \mu\text{A}$	-	200	1000	ppm/V
			$I_{load} = 4 \text{ mA}$	-	100	500	
$I_{load\_reg}$	Load regulation	$500 \mu\text{A} \leq I_{load} \leq 4 \text{ mA}$	Normal mode	-	50	500	ppm/mA
$T_{Coeff}$	Temperature coefficient	$-40^\circ\text{C} < T_J < +125^\circ\text{C}$		-	-	$T_{coeff\_vrefint} + 50$	ppm/°C
		$0^\circ\text{C} < T_J < +50^\circ\text{C}$		-	-	$T_{coeff\_vrefint} + 50$	
PSRR	Power supply rejection	DC		40	60	-	dB
		100 kHz		25	40	-	
$t_{START}$	Start-up time	$CL = 0.5 \mu\text{F}^{(4)}$		-	300	350	$\mu\text{s}$
		$CL = 1.1 \mu\text{F}^{(4)}$		-	500	650	
		$CL = 1.5 \mu\text{F}^{(4)}$		-	650	800	
$I_{INRUSH}$	Control of maximum DC current drive on VREFBUF_OUT during start-up phase <sup>(5)</sup>	-	-	-	8	-	mA

Table 86. COMP characteristics<sup>(1)</sup> (continued)

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
$I_{DDA}(COMP)$	Comparator consumption from $V_{DDA}$	Ultra-low-power mode	Static	-	400	600	nA
			With 50 kHz $\pm 100$ mV overdrive square signal	-	1200	-	
		Medium mode	Static	-	5	7	$\mu A$
			With 50 kHz $\pm 100$ mV overdrive square signal	-	6	-	
		High-speed mode	Static	-	70	100	
			With 50 kHz $\pm 100$ mV overdrive square signal	-	75	-	
$I_{bias}$	Comparator input bias current	-		-	-	_(4)	nA

1. Guaranteed by design, unless otherwise specified.

2. Refer to [Table 26: Embedded internal voltage reference](#).

3. Guaranteed by characterization results.

4. Mostly I/O leakage when used in analog mode. Refer to  $I_{lkg}$  parameter in [Table 71: I/O static characteristics](#).

### 6.3.22 Operational amplifiers characteristics

Table 87. OPAMP characteristics<sup>(1)</sup>

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{DDA}$	Analog supply voltage <sup>(2)</sup>	-	1.8	-	3.6	V
CMIR	Common mode input range	-	0	-	$V_{DDA}$	V
$V_{I\text{OFFSET}}$	Input offset voltage	25 °C, No Load on output.	-	-	$\pm 1.5$	mV
		All voltage/Temp.	-	-	$\pm 3$	
$\Delta V_{I\text{OFFSET}}$	Input offset voltage drift	Normal mode	-	$\pm 5$	-	$\mu V/^{\circ}C$
		Low-power mode	-	$\pm 10$	-	
TRIMOFFSETP TRIMLPOFFSETP	Offset trim step at low common input voltage ( $0.1 \times V_{DDA}$ )	-	-	0.8	1.1	mV
TRIMOFFSETN TRIMLPOFFSETN	Offset trim step at high common input voltage ( $0.9 \times V_{DDA}$ )	-	-	1	1.35	

Table 87. OPAMP characteristics<sup>(1)</sup> (continued)

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
e <sub>n</sub>	Voltage noise density	Normal mode	at 1 kHz, Output loaded with 4 kΩ	-	500	-	nV/√Hz
		Low-power mode	at 1 kHz, Output loaded with 20 kΩ	-	600	-	
		Normal mode	at 10 kHz, Output loaded with 4 kΩ	-	180	-	
		Low-power mode	at 10 kHz, Output loaded with 20 kΩ	-	290	-	
I <sub>DDA</sub> (OPAMP) <sup>(3)</sup>	OPAMP consumption from V <sub>DDA</sub>	Normal mode	no Load, quiescent mode	-	120	260	μA
		Low-power mode		-	45	100	

1. Guaranteed by design, unless otherwise specified.
2. The temperature range is limited to 0 °C-125 °C when V<sub>DDA</sub> is below 2 V
3. Guaranteed by characterization results.
4. Mostly I/O leakage, when used in analog mode. Refer to I<sub>lkg</sub> parameter in [Table 71: I/O static characteristics](#).
5. R2 is the internal resistance between OPAMP output and OPAMP inverting input. R1 is the internal resistance between OPAMP inverting input and ground. The PGA gain = 1+R2/R1

### 6.3.23 Temperature sensor characteristics

Table 88. TS characteristics

Symbol	Parameter	Min	Typ	Max	Unit
T <sub>L</sub> <sup>(1)</sup>	V <sub>TS</sub> linearity with temperature	-	±1	±2	°C
Avg_Slope <sup>(2)</sup>	Average slope	2.3	2.5	2.7	mV/°C
V <sub>30</sub>	Voltage at 30°C (±5 °C) <sup>(3)</sup>	0.742	0.76	0.785	V
t <sub>START</sub> (TS_BUF) <sup>(1)</sup>	Sensor Buffer Start-up time in continuous mode <sup>(4)</sup>	-	8	15	μs
t <sub>START</sub> <sup>(1)</sup>	Start-up time when entering in continuous mode <sup>(4)</sup>	-	70	120	μs
t <sub>S_temp</sub> <sup>(1)</sup>	ADC sampling time when reading the temperature	5	-	-	μs
I <sub>DD</sub> (TS) <sup>(1)</sup>	Temperature sensor consumption from V <sub>DD</sub> , when selected by ADC	-	4.7	7	μA

1. Guaranteed by design.
2. Guaranteed by characterization results.
3. Measured at V<sub>DDA</sub> = 3.0 V ±10 mV. The V<sub>30</sub> ADC conversion result is stored in the TS\_CAL1 byte. Refer to [Table 8: Temperature sensor calibration values](#).
4. Continuous mode means Run/Sleep modes, or temperature sensor enable in Low-power run/Low-power sleep modes.



Symbol	millimeters			inches <sup>(1)</sup>		
	Min	Typ	Max	Min	Typ	Max
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	15.800	16.000	16.200	0.6220	0.6299	0.6378
D1	13.800	14.000	14.200	0.5433	0.5512	0.5591
D3	-	12.000	-	-	0.4724	-
E	15.800	16.000	16.200	0.6220	0.6299	0.6378
E1	13.800	14.000	14.200	0.5433	0.5512	0.5591
E3	-	12.000	-	-	0.4724	-
e	-	0.500	-	-	0.0197	-
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
k	0.0°	3.5°	7.0°	0.0°	3.5°	7.0°
ccc	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

1. Dimensions are expressed in millimeters.

## 7.7 Thermal characteristics

The maximum chip-junction temperature,  $T_J$  max, in degrees Celsius, may be calculated using the following equation:

$$T_J \text{ max} = T_A \text{ max} + (P_D \text{ max} \times \Theta_{JA})$$

Where:

- $T_A$  max is the maximum ambient temperature in °C,
- $\Theta_{JA}$  is the package junction-to-ambient thermal resistance, in °C/W,
- $P_D$  max is the sum of  $P_{INT}$  max and  $P_{I/O}$  max ( $P_D \text{ max} = P_{INT} \text{ max} + P_{I/O} \text{ max}$ ),
- $P_{INT}$  max is the product of all  $I_{DDXXX}$  and  $V_{DDXXX}$ , expressed in Watts. This is the maximum chip internal power.

$P_{I/O}$  max represents the maximum power dissipation on output pins where:

$$P_{I/O} \text{ max} = \sum (V_{OL} \times I_{OL}) + \sum ((V_{DDIOx} - V_{OH}) \times I_{OH}),$$

taking into account the actual  $V_{OL} / I_{OL}$  and  $V_{OH} / I_{OH}$  of the I/Os at low and high level in the application.

**Table 111. Package thermal characteristics**

Symbol	Parameter	Value	Unit
$\Theta_{JA}$	<b>Thermal resistance junction-ambient</b> LQFP100 - 14 × 14 mm / 0.5 mm pitch	56	°C/W
	<b>Thermal resistance junction-ambient</b> UFBGA100 - 7 × 7 mm / 0.5 mm pitch	75	
	<b>Thermal resistance junction-ambient</b> LQFP64 - 10 × 10 mm / 0.5 mm pitch	58	
	<b>Thermal resistance junction-ambient</b> UFBGA64 - 5 × 5 mm / 0.5 mm pitch	65	
	<b>Thermal resistance junction-ambient</b> WLCSP64 3.141 × 3.127 / 0.35 mm pitch	53	
	<b>Thermal resistance junction-ambient</b> UFQFPN48 - 7 × 7 mm / 0.5 mm pitch	29	

### 7.7.1 Reference document

JESD51-2 Integrated Circuits Thermal Test Method Environment Conditions - Natural Convection (Still Air). Available from [www.jedec.org](http://www.jedec.org)

### 7.7.2 Selecting the product temperature range

When ordering the microcontroller, the temperature range is specified in the ordering information scheme shown in [Section 8: Ordering information](#).

Each temperature range suffix corresponds to a specific guaranteed ambient temperature at maximum dissipation and, to a specific maximum junction temperature.

As applications do not commonly use the STM32L452xx at maximum dissipation, it is useful to calculate the exact power consumption and junction temperature to determine which temperature range will be best suited to the application.

The following examples show how to calculate the temperature range needed for a given application.

### Example 1: High-performance application

Assuming the following application conditions:

Maximum ambient temperature  $T_{Amax} = 75\text{ °C}$  (measured according to JESD51-2),  
 $I_{DDmax} = 50\text{ mA}$ ,  $V_{DD} = 3.5\text{ V}$ , maximum 20 I/Os used at the same time in output at low level with  $I_{OL} = 8\text{ mA}$ ,  $V_{OL} = 0.4\text{ V}$  and maximum 8 I/Os used at the same time in output at low level with  $I_{OL} = 20\text{ mA}$ ,  $V_{OL} = 1.3\text{ V}$

$$P_{INTmax} = 50\text{ mA} \times 3.5\text{ V} = 175\text{ mW}$$

$$P_{IOmax} = 20 \times 8\text{ mA} \times 0.4\text{ V} + 8 \times 20\text{ mA} \times 1.3\text{ V} = 272\text{ mW}$$

This gives:  $P_{INTmax} = 175\text{ mW}$  and  $P_{IOmax} = 272\text{ mW}$ :

$$P_{Dmax} = 175 + 272 = 447\text{ mW}$$

Using the values obtained in [Table 111](#)  $T_{Jmax}$  is calculated as follows:

– For LQFP64,  $58\text{ °C/W}$

$$T_{Jmax} = 75\text{ °C} + (58\text{ °C/W} \times 447\text{ mW}) = 75\text{ °C} + 25.926\text{ °C} = 100.926\text{ °C}$$

This is within the range of the suffix 6 version parts ( $-40 < T_J < 105\text{ °C}$ ) see [Section 8: Ordering information](#).

In this case, parts must be ordered at least with the temperature range suffix 6 (see Part numbering).

**Note:** *With this given  $P_{Dmax}$  we can find the  $T_{Amax}$  allowed for a given device temperature range (order code suffix 6 or 3).*

$$\text{Suffix 6: } T_{Amax} = T_{Jmax} - (58\text{ °C/W} \times 447\text{ mW}) = 105 - 25.926 = 79.074\text{ °C}$$

$$\text{Suffix 3: } T_{Amax} = T_{Jmax} - (58\text{ °C/W} \times 447\text{ mW}) = 130 - 25.926 = 104.074\text{ °C}$$

### Example 2: High-temperature application

Using the same rules, it is possible to address applications that run at high ambient temperatures with a low dissipation, as long as junction temperature  $T_J$  remains within the specified range.

Assuming the following application conditions:

Maximum ambient temperature  $T_{Amax} = 100\text{ °C}$  (measured according to JESD51-2),  
 $I_{DDmax} = 20\text{ mA}$ ,  $V_{DD} = 3.5\text{ V}$ , maximum 20 I/Os used at the same time in output at low level with  $I_{OL} = 8\text{ mA}$ ,  $V_{OL} = 0.4\text{ V}$

$$P_{INTmax} = 20\text{ mA} \times 3.5\text{ V} = 70\text{ mW}$$

$$P_{IOmax} = 20 \times 8\text{ mA} \times 0.4\text{ V} = 64\text{ mW}$$

This gives:  $P_{INTmax} = 70\text{ mW}$  and  $P_{IOmax} = 64\text{ mW}$ :

$$P_{Dmax} = 70 + 64 = 134\text{ mW}$$

Thus:  $P_{Dmax} = 134\text{ mW}$

Using the values obtained in [Table 111](#)  $T_{Jmax}$  is calculated as follows:

– For LQFP64,  $58\text{ °C/W}$

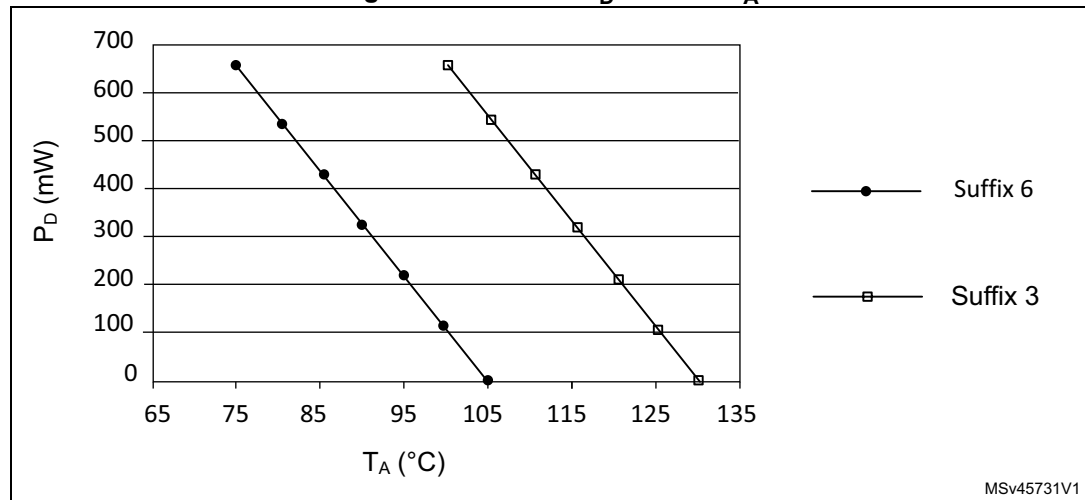
$$T_{Jmax} = 100\text{ °C} + (58\text{ °C/W} \times 134\text{ mW}) = 100\text{ °C} + 7.772\text{ °C} = 107.772\text{ °C}$$

This is above the range of the suffix 6 version parts ( $-40 < T_J < 105\text{ °C}$ ).

In this case, parts must be ordered at least with the temperature range suffix 3 (see [Section 8: Ordering information](#)) unless we reduce the power dissipation in order to be able to use suffix 6 parts.

Refer to [Figure 59](#) to select the required temperature range (suffix 6 or 3) according to your ambient temperature or power requirements.

Figure 59. LQFP64  $P_D$  max vs.  $T_A$



**IMPORTANT NOTICE – PLEASE READ CAREFULLY**

STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, enhancements, modifications, and improvements to ST products and/or to this document at any time without notice. Purchasers should obtain the latest relevant information on ST products before placing orders. ST products are sold pursuant to ST's terms and conditions of sale in place at the time of order acknowledgement.

Purchasers are solely responsible for the choice, selection, and use of ST products and ST assumes no liability for application assistance or the design of Purchasers' products.

No license, express or implied, to any intellectual property right is granted by ST herein.

Resale of ST products with provisions different from the information set forth herein shall void any warranty granted by ST for such product.

ST and the ST logo are trademarks of ST. All other product or service names are the property of their respective owners.

Information in this document supersedes and replaces information previously supplied in any prior versions of this document.

© 2018 STMicroelectronics – All rights reserved